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## Correction: Testing and validating electroanalytical simulations

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Correction for 'Testing and validating electroanalytical simulations' by Enno Kätelhön and Richard G. Compton, *Analyst*, 2015, DOI: 10.1039/c4an02276a.

In eqn (15), we provide an expression for the voltammetric peak separation in a voltammogram recorded under Nernstian conditions and a 1 : 1 stoichiometry at a microdisk electrode:

$$\Delta E_{pp} = 2.218 \frac{RT}{nF} \quad (15)$$

Following this equation it should say "...in the limit of fast scan rates,  $\sigma \rightarrow \infty$ , or in the large-electrode limit. In the  $\sigma \rightarrow 0$  limit the voltammetric peaks disappear and  $\Delta E_{pp}$  is no longer helpful."

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.

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